

GPI65060DFC

N-channel 650 V 60 A GaN Power HEMT in DFN8x8 package

Datasheet version: 1.0

BV _{dss}	R _{dson}	l _{ds}	Qg
650 V	25 mΩ	60 A	16 nC

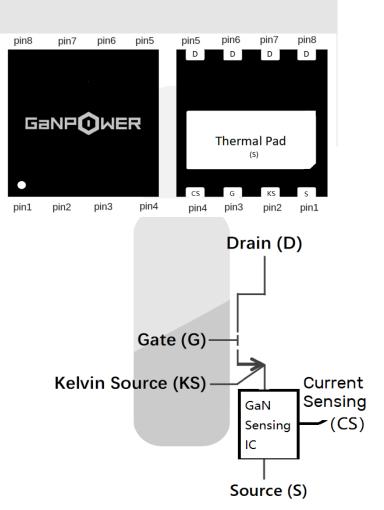
- Ultra-low RDS(on)
- High dv/dt capability
- Extremely low input capacitance
- Zero Qrr

Features

- Outstanding switching performance
- Low Profile

Applications

- Switching Power Applications
- Server and Telecom Power Applications
- EV OBC and DC-DC Converters



Description

These devices are N-channel 650 V Power GaN HEMTs based on proprietary E-mode GaN on silicon technology. The resulting product has extremely low on state resistance, very low input capacitance and zero reverse recovery charge making it especially suitable for applications which require superior power density, ultra-high switching frequency and outstanding efficiency. Besides, an in-line lossless GaN current sensing IC is integrated for sensing current.



Device Characteristics

Static Parameters			Test data				
	Parameters		Conditions	Min	Typical	Max	Unit
1	V _{gs(TH)}	Gate threshold voltage	V _{ds} =V _{gs} Id=3.5mA	1.0	1.2	1.4	V
2	BV _{dss}	Drain-Source breakdown voltage	V _{gs} =0V I _d =25uA		650		V
3	l _{dss}	Zero gate voltage drain current, T _c = 25℃	V _{gs} =0V V _{ds} =650V		1.5	50	uA
4	l _{gss}	Gate-Source Leakage	$V_{gs} = 6V$ $V_{ds} = 0V$		347		uA
5	R _{dson}	Static drain-source on resistance, $T_c = 25^{\circ}C$	V _{gs} =6V I _d =2.5A		25	35	mΩ
6	V_{sd}	Reverse conduction voltage	I _{sd} =1A V _{gs} =0V	1.55	1.75	2.0	V
7	R _g	Gate resistance	F=25MHz Open drain		2.18		Ω
	Dynamic Parameters		Test data				
Dyı	namic Paramet	ers			Test da	ata	
Dyı	Parameters	ers	Conditions	Min	Test da Typical	ata Max	Unit
Dyı	Parameters C _{iss}	Input capacitance	V _{gs} =0V	Min			pf
Dyr 1	Parameters C _{iss} C _{oss}	Input capacitance Output capacitance	V _{gs} =0V V _{ds} =400V	Min	Typical 420 143		pf pf
	Parameters C _{iss} C _{oss} C _{rss}	Input capacitance Output capacitance Reverse transfer capacitance	V _{gs} =0V	Min	Typical 420 143 6		pf pf pf
1	Parameters C _{iss} C _{oss} C _{rss} Q _g	Input capacitance Output capacitance Reverse transfer capacitance Gate charge	V _{gs} =0V V _{ds} =400V f=1MHz V _{ds} =400V	Min	Typical 420 143		pf pf
	Parameters C _{iss} C _{oss} C _{rss}	Input capacitance Output capacitance Reverse transfer capacitance Gate charge Gate to source charge	$V_{gs}=0V \\ V_{ds}=400V \\ f=1MHz \\ V_{ds}=400V \\ I_{d}=7.5A$	Min	Typical 420 143 6 16.1 1.1		pf pf pf
1	Parameters C _{iss} C _{oss} C _{rss} Q _g Q _{gs} Q _{gd}	Input capacitance Output capacitance Reverse transfer capacitance Gate charge Gate to source charge Gate to drain charge	V _{gs} =0V V _{ds} =400V f=1MHz V _{ds} =400V	Min	Typical 420 143 6 16.1 1.1 1.8		pf pf pf nC nC nC
1	Parameters C _{iss} C _{oss} C _{rss} Q _g Q _{gs}	Input capacitance Output capacitance Reverse transfer capacitance Gate charge Gate to source charge	$V_{gs}=0V \\ V_{ds}=400V \\ f=1MHz \\ V_{ds}=400V \\ I_{d}=7.5A$	Min	Typical 420 143 6 16.1 1.1		pf pf pf nC nC
1 3 2	Parameters C _{iss} C _{oss} C _{rss} Q _g Q _{gs} Q _{gd}	Input capacitance Output capacitance Reverse transfer capacitance Gate charge Gate to source charge Gate to drain charge Reverse recovery charge	$V_{gs}=0V \\ V_{ds}=400V \\ f=1MHz \\ V_{ds}=400V \\ I_{d}=7.5A$	Min	Typical 420 143 6 16.1 1.1 1.8	Max	pf pf pf nC nC nC
1 3 2	Parameters C _{iss} C _{oss} C _{rss} Q _g Q _{gs} Q _{gd} Q _{rr}	Input capacitance Output capacitance Reverse transfer capacitance Gate charge Gate to source charge Gate to drain charge Reverse recovery charge	$V_{gs}=0V \\ V_{ds}=400V \\ f=1MHz \\ V_{ds}=400V \\ I_{d}=7.5A$	Min	Typical 420 143 6 16.1 1.1 1.8 0	Max	pf pf pf nC nC nC
1 3 2	Parameters C _{iss} C _{oss} C _{rss} Q _g Q _{gs} Q _{gd} Q _{rr} itching Perform	Input capacitance Output capacitance Reverse transfer capacitance Gate charge Gate to source charge Gate to drain charge Reverse recovery charge	$V_{gs}=0V \\ V_{ds}=400V \\ f=1MHz \\ V_{ds}=400V \\ I_{d}=7.5A \\ V_{gs}=6V \\ \hline \\ $		Typical 420 143 6 16.1 1.1 1.8 0 Test data	Max	pf pf nC nC nC nC
1 3 2 Swi	Parameters C _{iss} C _{oss} C _{rss} Q _g Q _{gs} Q _{gd} Q _{rr} tching Perform	Input capacitance Output capacitance Reverse transfer capacitance Gate charge Gate to source charge Gate to drain charge Reverse recovery charge	$V_{gs}=0V \\ V_{ds}=400V \\ f=1MHz \\ V_{ds}=400V \\ I_{d}=7.5A \\ V_{gs}=6V \\ \hline \\ $		Typical 420 143 6 16.1 1.1 1.8 0 Test da Typical	Max	pf pf nC nC nC nC
1 3 2 Swi 1	Parameters Ciss Coss Crss Qg Qgs Qgd Qrr itching Perform Parameters td(on)	Input capacitance Output capacitance Reverse transfer capacitance Gate charge Gate to source charge Gate to drain charge Reverse recovery charge	$V_{gs}=0V \\ V_{ds}=400V \\ f=1MHz \\ V_{ds}=400V \\ I_{d}=7.5A \\ V_{gs}=6V \\ \hline \\ $		Typical 420 143 6 16.1 1.1 1.8 0 Test da Typical 9	Max	pf pf nC nC nC nC nC nC



Absolute Max. Ratings

	Symbols	Parameters	Value	Unit
1	V _{DS-max}	Breakdown voltage transient @ T _{case} =25°C	800	V
2	V_{GS-max}	Gate to source max. transient voltage @ T _{case} =25°C	-12 to +7.5	V
3	I _{ds-max}	Drain to source DC current @ T _{case} =25°C	60	А
4	l _{ds-max}	Drain to source DC current @ T _{case} =100°C	50	А
5	dv/dt- _{max}	Drain to source voltage slew rate	200	V/ns
6	T _{J-max}	Max junction temperature	150	°C
7	T _{S-storage}	Storage temperature	-55 to 150	°C

Thermal and Soldering Characteristics (Typical)

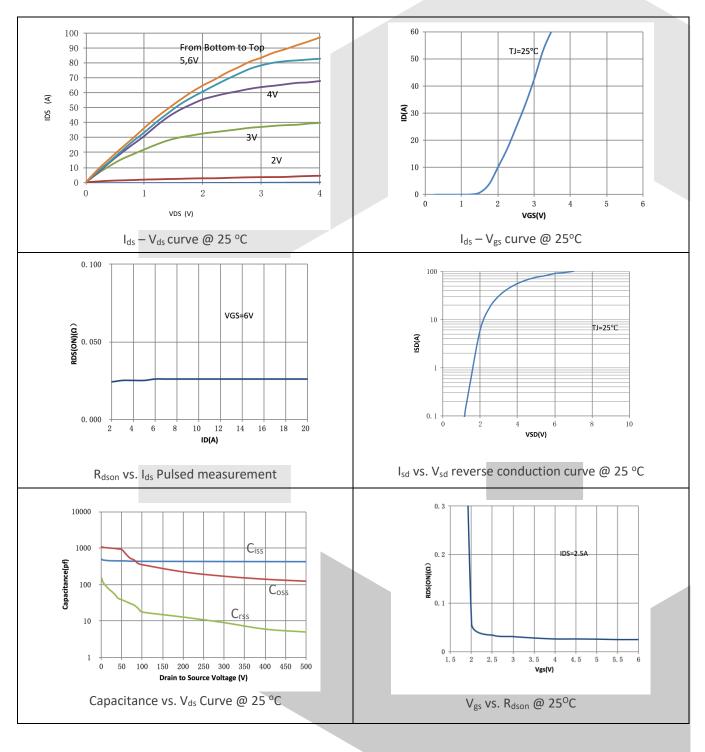
	Symbols	Parameters	Value	Unit
1	R_{thJC}	Thermal resistance (junction to case)	0.6	°C /W
2	R_{thJA}	Thermal resistance (junction to ambient)	62	°C /W
2	T _{solder}	Reflow soldering temperature	260	°C

Ordering

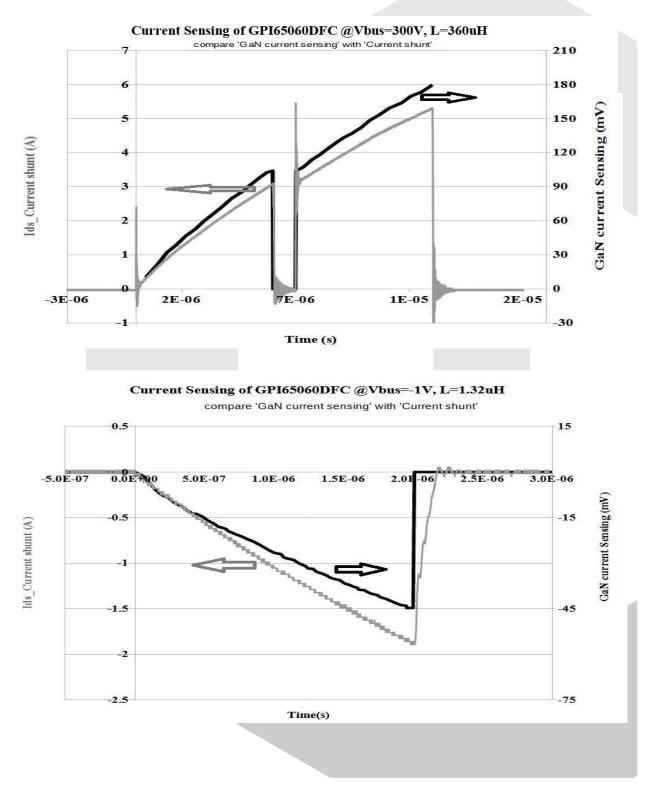
Order Code	Package Type	Packaging Method	Qty
GPI65060DFC	DFN 8x8	QFN/DFN-Tray	100



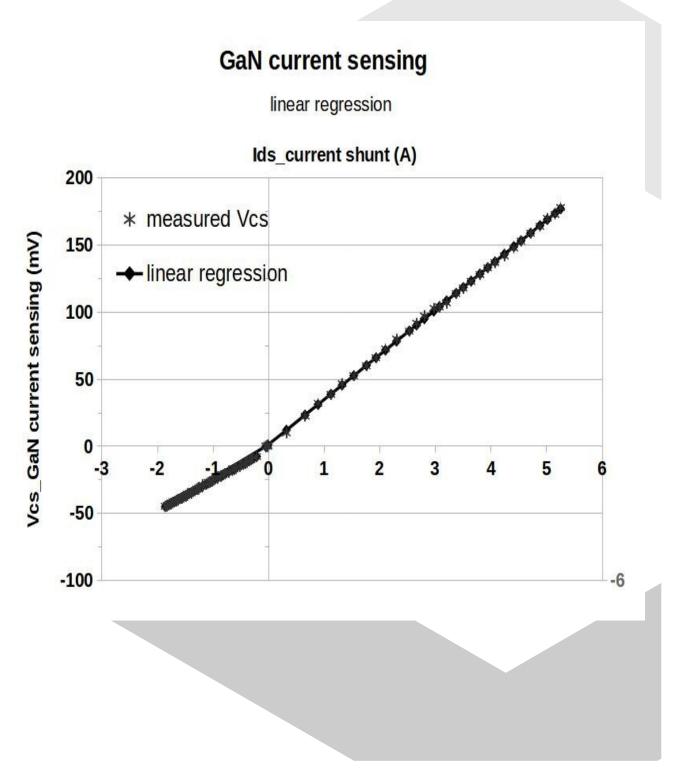
Electrical Performance





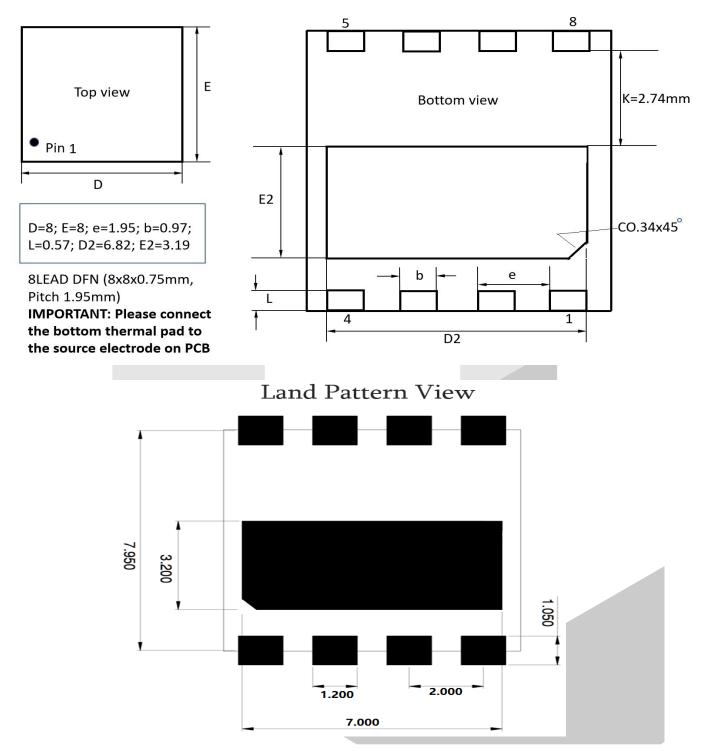








Package Information





GaN HEMT Frequently Asked Questions

1	Q: Can we do pin to pin switch for silicon MOSFET or IGBT?
	A: The short answer is no. GaN HEMT power devices are far superior than the best silicon
	devices such as super junction MOSFETs. However, due to different requirements of gate
	driving voltage and extremely high dv/dt slew rate, special drivers and optimized PCB layouts
	are recommended to minimize the impact from circuit parasitics. Some packaging forms such
	as GaNPower's DFN packaged devices offer both sense and force for the source terminal. Also,
	for traditional TO220 packages, please be advised that the pins are arranged as Gate – Source
	-Drain, and the thermal pad is connected to the source instead of drain.
2	Q: Are GaN power devices reliable?
	A: GaN power HEMTs have been tested by GaNPower and many other vendors, users and
	testing facilities to be as reliable (if not better than) silicon counterparts.
3	Q: How do GaN power devices compare with SiC?
	A: Currently GaN power HEMT devices are most suitable for low to medium voltage (\leq 1200V)
	and power (<20KW) applications. GaN is the ideal choice for high frequency applications. SiC
	devices are better choice for high voltage and high-power applications (>20KW).
4	Q: Do we need to parallel an FRD for applications such as inverters?
	A: GaN devices are different from silicon MOSFET or IGBT in that they have no inherent PN
	junction diodes that cause reverse recovery issue. User do not need to parallel an FRD for the
	purpose of suppressing the body diode reverse recovery effect, since GaN HEMT can operate
	in both first and third quadrants. However, care should be taken for the dead time power loss
	since the Vsd voltage of GaN HEMT is usually close to 2V. This is especially true when a negative
	gate voltage is applied.
6	Q: Can we parallel GaN HEMT devices?
	A: Yes, GaN HEMT is ideal for paralleling, due to positive temperature coefficient of Rdson
<u> </u>	and slightly positive temperature coefficient of threshold voltage.
5	Q: Where can we find drivers for GaNPower HEMT devices?
	A: While some of the GaNPower's HEMTs are either monolithically integrated with gate
	driver or co-packaged with a silicon driver, drivers can be easily found from vendors such as
	TI and Silicon Lab for either single sided or half-bridge configurations:
	✓ <u>TI: LM5114</u> : Single 7.6A Peak Current Low-Side Gate Driver
	✓ <u>TI: UCC27611</u> : 5V, 4A/6A Low Side GaN Driver
	Maxim: MAX5048C: 7A Sink/3A Source Current, 8ns, SOT23, MOSFET Drive
	✓ Fairchild: FAN3122: Single 9-A High-Speed, Low-Side Gate Driver
	✓ <u>Silicon Lab: Si827X</u> : 4 Amp ISO driver with High Transient (dv/dt) Immunity